



On-line Conveyor XRF Analyzer CON-X

Application

On-line XRF conveyor analyzer CON-X identifies and measures the concentrations of elements and minerals in ores and other materials on a conveyor belt.

The analyzer detects elements from Al (Z=13) to U (Z=92)

Fields of application

- concentration measurements in mining, reprocessing and metallurgy industry
- ready-made applications for: K, Ca, Ti, V, Cr, Mn, Fe, Co, Ni, Cu, Zn, Ge analysis in different types of ore. Haven't found the interesting element? Contact us: xrf-sales@bsi.lv

Features

- on-line non-destructive analysis of material composition directly above a conveyor belt
- high precision and stability of results in severe environments: dust, low/high temperature and humidity
- stable measurement results with varying lump size, relative humidity and distance in the allowable range (6-25 cm)
- modifications available for light and heavy element analysis
- simple and convenient operation and service
- empty belt exclusion algorithm
- remote support through Internet
- instrument control and data results provided using OPC communication, 4-20 mA output, Ethernet

Fast pay-back and savings

- savings in raw material used
- savings in time due to the fast analysis
- increased plant's productivity

Bringing Solutions







Specifications

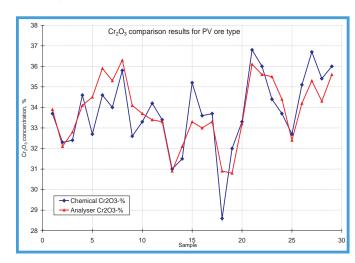
| Parameters | CON-X |
|--|------------------|
| Detector type: | SDD detector |
| Energy resolution at 5,9 keV (Mn-K _a), eV: | 160 |
| Radiation source: | X-ray tube |
| Concentration range with measurement time of 5 min: | |
| - for Al, Si, P | from 8 to 80% |
| - for S, Cl, K, Ca | from 2 to 95% |
| - for Ti, V, Cr, Mn, Fe, Co, Ni, Cu, Zn | from 0,02 to 99% |
| Dimensions, mm: | 890 x 275 x 240 |
| Weight without fixing elements, kg: | 45 |
| Enclosure protection: | IP 65 |
| Operational temperature range, °C: | -20 + 40 |

The mean square deviation of concentration measurement results in static mode and concentration range 0.5...90% is $\pm 0.25\%$. The precision of analysis could change depending on the application.

Display window of the CON-X software

| Constitute | Con

Comparison of results with chemical method



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